



Edition 2.0 2009-11

INTERNATIONAL STANDARD

NORME **INTERNATIONALE**

AMENDMENT 2 AMENDEMENT 2

Magnetic material **Feh** STANDARD PREVIEW Part 3: Methods of measurement of the magnetic properties of electrical steel strip and sheet by means of a single sheet tester

IEC 60404-3:1992/AMD2:2009

Matériaux magnétiques Partie 3: Méthodes de mesure/des caractéristiques magnétiques des bandes et tôles magnétiques en acier à l'aide de l'essai sur tôle unique





THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2009 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester.

If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de la CEI ou du Comité national de la CEI du pays du demandeur. Si vous avez des questions sur le copyright de la CEI ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de la CEI de votre pays de résidence.

IEC Central Office 3, rue de Varembé CH-1211 Geneva 20 Switzerland Email: inmail@iec.ch Web: www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

Catalogue of IEC publications: www.ieo.ch/searchpub ARD PREVIEW

The IEC on-line Catalogue enables you to search by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, withdrawn and replaced publications.

IEC Just Published: www.iec.ch/online news/justpub
Stay up to date on all new IEC publications. Just Published details twice a month all new publications released. Available on-line and also by email.
IEC 60404-3:1992/AMD2:2009

Electropedia: www.electropedia.org.ds.iteh.ai/catalog/standards/sist/c4142d3a-1b68-4d62-8c2c-

The world's leading online dictionary of electronic and electrical terms containing more than 20 000 terms and definitions in English and French, with equivalent terms in additional languages. Also known as the International Electrotechnical Vocabulary online.

Customer Service Centre: <u>www.iec.ch/webstore/custserv</u>

If you wish to give us your feedback on this publication or need further assistance, please visit the Customer Service Centre FAQ or contact us:

Email: <u>csc@iec.ch</u> Tel.: +41 22 919 02 11 Fax: +41 22 919 03 00

A propos de la CEI

La Commission Electrotechnique Internationale (CEI) est la première organisation mondiale qui élabore et publie des normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

A propos des publications CEI

Le contenu technique des publications de la CEI est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

Catalogue des publications de la CEI: <u>www.iec.ch/searchpub/cur_fut-f.htm</u>

Le Catalogue en-ligne de la CEI vous permet d'effectuer des recherches en utilisant différents critères (numéro de référence, texte, comité d'études,...). Il donne aussi des informations sur les projets et les publications retirées ou remplacées.

Just Published CEI: www.iec.ch/online_news/justpub

Restez informé sur les nouvelles publications de la CEI. Just Published détaille deux fois par mois les nouvelles publications parues. Disponible en-ligne et aussi par email.

Electropedia: <u>www.electropedia.org</u>

Le premier dictionnaire en ligne au monde de termes électroniques et électriques. Il contient plus de 20 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans les langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International en ligne.

Service Clients: <u>www.iec.ch/webstore/custserv/custserv_entry-f.htm</u>

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions, visitez le FAQ du Service clients ou contactez-nous:

Email: <u>csc@iec.ch</u> Tél.: +41 22 919 02 11

Fax: +41 22 919 03 00





Edition 2.0 2009-11

INTERNATIONAL STANDARD

NORME INTERNATIONALE

AMENDMENT 2 AMENDEMENT 2

Magnetic material**sTeh STANDARD PREVIEW**

Part 3: Methods of measurement of the magnetic properties of electrical steel strip and sheet by means of a single sheet tester

IEC 60404-3:1992/AMD2:2009

Matériaux magnétiques de mesure des caractéristiques magnétiques des bandes et tôles magnétiques en acier à l'aide de l'essai sur tôle unique

INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

PRICE CODE CODE PRIX



ICS 17.220.20; 29.030

ISBN 978-2-88910-185-6

FOREWORD

This amendment has been prepared by IEC technical committee 68: Magnetic alloys and steels.

The text of this amendment is based on the following documents:

CDV	Report on voting
68/389/CDV	68/397/RVC

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

iTeh STANDARD PREVIEW

The contents of the corrigendum of December 2009 have been included in this copy.

IEC 60404-3:1992/AMD2:2009 https://standards.iteh.ai/catalog/standards/sist/c4142d3a-1b68-4d62-8c2cc43601e7596f/iec-60404-3-1992-amd2-2009

Title

Amend the title of this standard on the cover page, the title page, and before the Foreword and Clause 1 as follows:

Replace "magnetic sheet and strip" by "electrical steel strip and sheet".

2 Normative references

Replace the existing references by the following:

IEC 60050-221, International Electrotechnical Vocabulary – Part 221: Magnetic materials and components

IEC 60404-2, Magnetic materials – Part 2: Methods of measurement of the magnetic properties of electrical steel strip and sheet by means of an Epstein frame

4.2.1 Voltage measurement

Insert, after the subclause title and before 4.2.1.1 the following new note:

NOTE For the application of digital sampling methods, see Annex D.

60404-3 Amend. 2 © IEC:2009 - 3 -

4.2.2 Frequency measurement

Introduce the following note after the paragraph:

NOTE For the application of digital sampling methods, see Annex D.

4.2.3 Power measurement

Introduce the following note after the first paragraph:

NOTE For the application of digital sampling methods, see Annex D.

4.3 Measurement procedure

Replace the existing title by the following new title:

4.3 Measurement procedure of the specific total loss

Introduce the following note after the clause heading:

NOTE For the application of digital sampling methods, see Annex D.

iTeh STANDARD PREVIEW

Add the following new Annex D. (standards.iteh.ai)

IEC 60404-3:1992/AMD2:2009 https://standards.iteh.ai/catalog/standards/sist/c4142d3a-1b68-4d62-8c2cc43601e7596f/iec-60404-3-1992-amd2-2009

Annex D (informative)

Digital sampling methods for the determination of the magnetic properties

D.1 General

The digital sampling method is an advanced technique that is becoming almost exclusively applied to the electrical part of the measurement procedure of this standard. It is characterized by the digitalization of the secondary voltage, $U_2(t)$, the voltage drop across the non-inductive precision resistor in series with the primary winding (see Figures 4 and 6), $U_1(t)$, and the evaluation of the data for the determination of the magnetic properties of the test specimen. For this purpose, instantaneous values of these voltages having index *j*, u_{2j} and u_{1j} respectively, are sampled and held simultaneously from the time-dependent voltage functions during a narrow and equidistant time period each by sample-and-hold circuits. They are then immediately converted to digital values by analog-to-digital converters (ADC). The data pairs sampled over one or more periods together with the specimen and the set-up parameters, provide the complete information for one measurement. This data set enables computer processing for the determination of all magnetic properties required in this standard.

The digital sampling method may be applied to the measurement procedures which are described in the main part of this standard. The block diagram in Figure 4 applies equally to the analogue methods and the digital sampling method, the digital sampling method allows all functions of the measurement equipments in Figure 4 to 6 to be realized by a combined system of a data acquisition equipment and software. The control of the sinusoidal waveform of the secondary voltage can also be realized by a digital method. However, the purpose and procedure of this technique are different from those of this annex and are not treated here. More information can be found in [3] and [4] 60404-3-1992-and2-2009

This annex is helpful in understanding the impact of the digital sampling method on the precision achievable by the methods of this standard. This is particularly important because ADC circuits, transient recorders and supporting software are easily available thus encouraging one to build one's own wattmeter. The digital sampling method can offer low uncertainty, but it leads to large errors if improperly used.

D.2 Technical details and requirements

The principle of the digital sampling method is the discretization of voltage and time, i.e. the replacement of the infinitesimal time interval dt by the finite time interval Δt :

$$\Delta t = \frac{T}{n} = \frac{1}{f \cdot n} = \frac{1}{f_{\rm S}} \tag{D.1}$$

where

- Δt is the time interval between the sampled points, in seconds;
- *T* is the length of the period of the magnetization, in seconds;
- *n* is the number of instantaneous values sampled over one period;
- f is the frequency of the magnetization, in hertz;
- $f_{\rm s}$ is the sampling frequency, in points per seconds.

In order to achieve lower uncertainties, the length of the period of the magnetization divided by the time interval between the sampled points, i.e. the ratio f_s/f , should be an integer (Nyquist condition [7]) and the sampling frequency, f_s , should be greater than twice the input signal bandwidth.

According to an average-sensing voltmeter, the peak value of the flux density can be calculated by the sum of the u_{2i} values sampled over one period as follows:

$$\hat{J} = \frac{1}{4fN_2A} \frac{1}{T} \int_{t=0}^{T} |U_2(t)| dt \simeq \frac{1}{4f_s N_2 A} \sum_{j=0}^{n-1} |u_{2j}|$$
(D.2)

The calculation of the specific total loss is carried out by point-by-point multiplication of the u_{2i} and u_{1i} values and summation over one period as follows¹:

$$P_{s} = \frac{N_{1}}{I_{m}RN_{2}A\rho_{m}} \frac{1}{T} \int_{t=0}^{T} U_{1}(t)U_{2}(t)dt \cong \frac{N_{1}}{I_{m}RN_{2}A\rho_{m}} \frac{1}{n} \sum_{j=0}^{n-1} u_{1j}u_{2j}$$
(D.3)

where

- Ĵ is the peak value of the magnetic polarization, in teslas;
- is the specific total loss of the specimen, in watts per kilogram; $P_{\rm s}$
- is the length of the period of the magnetization, in seconds; Т
- is the frequency of the magnetizationain hertz; teh.ai) f
- is the sampling frequency, in points per second; fs
- is the number of turns of the primary winding: https://standards.iteh.al/catalog/standards/sist/c4142d3a-1b68-4d62-8c2c- N_1
- is the number of turns of the secondary (winding 92-and 2-2009) N_2
- Α is the cross-sectional area of the test specimen, in square metres;
- R is the resistance of the non-inductive precision resistor R in series with the primary winding (see Figure 6), in ohms;
- is the voltage drop across the non-inductive precision resistor R, in volts; U_1
- U_2 is the secondary voltage, in volts;
- is the number of instantaneous values sampled over one period; n
- is the index of instantaneous values:
- is the conventional effective magnetic path length, in metres ($I_{\rm m}$ = 0,45 m; for I_m measurements in connection with a calibration by means of Epstein measurements, see Annex B);
- is the conventional density of the test material, in kilograms per cubic metre. $\rho_{\rm m}$

$$\hat{H} = \frac{N_1}{RI_m}\hat{U}_1$$
 and $S_s \cong \frac{N_1}{I_m RN_2 A \rho_m} \sqrt{\frac{1}{n} \sum_{j=0}^n u_{1j}^2} \sqrt{\frac{1}{n} \sum_{j=0}^n u_{2j}^2}$

The peak value of the magnetic field strength and the apparent power can be calculated correspondingly by using

The pairs of values, u_{2i} and u_{1i} , can then be processed by a computer or, for real time processing, by a digital signal processor (DSP) using a sufficiently fast digital multiplier and adder without intermediate storage being required. Keeping the Nyquist condition is possible only where the sampling frequency f_s and the frequency f of the magnetization are derived from a common high frequency clock and thus, have an integer ratio f_s/f . In that case, $U_1(t)$ and $U_2(t)$ may be scanned using 128 samples per period with sufficient accuracy. This figure is, according to the Shannon theorem, determined by the highest relevant frequency in the H(t) signal, which is normally not higher than that of the 41st harmonic [5]. However, some commercial data acquisition equipment cannot be synchronized with the frequency of the magnetization and, as a consequence, the ratio f_s/f is not an integer, i.e. the Nyquist condition is not met. In that case, the sampling frequency must be considerably higher (500 samples per period or more) in order to keep the deviation of the true period length from the nearest time of sampled point small. Keeping the Nyquist condition becomes a decisive advantage in the case of higher frequency applications (for instance at 400 Hz which is within the scope of this standard). The use of a low-pass anti-aliasing filter [7] is recommended in order to eliminate irrelevant higher frequency components which would otherwise interact with the digital sampling process producing aliasing noise.

Regarding the amplitude resolution, studies [5, 6] have shown that below a 12 bit resolution, the digitalization error can be considerable, particularly for non-oriented material with high silicon content. Thus, at least a 12 bit resolution of the given amplitude is recommended. Moreover, the two voltage channels should transfer the signals without a significant phase shift. The phase shift should be small enough so that the power measurement uncertainty specified in this standard, namely 0,5 %, is not exceeded. The consideration of the phase shift is more relevant the lower the power factor $\cos(\varphi)$ becomes (φ being the phase shift between the fundamental components of the two voltage signals). For this reason the concept of a single channel with multiplexer leading to different sampling times for the instantaneous values of the two voltages is not to be recommended.

Signal conditioning amplifiers are preferably d.c. coupled to avoid any low frequency phase shift. However, d.c. offsets in the signal conditioning amplifiers can lead to significant errors in the numerically calculated values. Numerical correction cancelling can be applied to remove such d.c. offsets.

D.3 Calibration aspects

The verification of the repeatability and reproducibility requirements of this standard make careful calibration of the measurement equipment necessary. The two voltage channels including preamplifiers and ADC can be calibrated using a calibrated reference a.c. voltage source [8]. In addition, the phase performance of the two channels and its dependence on the frequency should be verified and possibly be taken into account with the evaluation processing in the computer. In any case, it would not be sufficient to calibrate the set-up using reference samples because that calibration would only be effective for that combination of material and measurement condition.

Bibliography

Replace the existing Bibliography with the following new Bibliography:

Bibliography

- [1] SIEVERT, J., AHLERS, H., BROSIN, P., CUNDEVA, M. and LUEDKE, J. Relationship of Epstein to SST Results for Grain-Oriented Steel. 9th ISEM Conference (1999), published in: P.di Barba, A.Savini (editors): Non-Linear Electromagnetic Systems, ISEM'99, Studies in Applied Electromagnetics and Mechanics, Vol. 18, IOS Press, Amsterdam, 2000, p.3-6.
- [2] SIEVERT, J. The Measurement of Magnetic Properties of Electrical Sheet Steel Survey on Methods and Situation of Standards. SMM 14 Conference, Balatonfuered, Hungary, September 1999, J.Magn.Magn. Mater., 215-215 (2000) p. 647-651.
- [3] FIORILLO, F., *Measurement and characterization of magnetic materials*. Elsevier Series in Electromagnetism. Academic Press (2004), ISBN: 0-12-257251-3.
- [4] Annex B: "Sinusoidal waveform control by digital means" from IEC 60404-6:2003, Magnetic materials – Part 6: Methods of measurement of the magnetic properties of magnetically soft metallic and powder materials at frequencies in the range 20 Hz to 200 kHz by the use of ring specimens (standards.iteh.ai)
- [5] AHLERS, H. and SIEVERT, J., Uncertainties of Magnetic Loss Measurements, particularly in Digital Procedures6(PTB3Mitt2/94/(1984)) p. 99-107. https://standards.iteh.ai/catalog/standards/sist/c4142d3a-1b68-4d62-8c2c-
- [6] De WULF, M. and MELKEBEER, On the advantage and drawbacks of using digital acquisition systems for the determination of magnetic properties of electrical steel sheet and strip. J. Magn. Magn. Mater., 196-197 (1999) p.940-942.
- [7] STEARNS, S.D., *Digital signal analysis*. 5th Edition, Hayden Book (1991), ISBN:0-8104 5828-4.
- [8] AHLERS, H., Precision calibration procedure for magnetic loss testers using a digital two-channel function generator. SMM11 Venice 1993, J. Magn. Magn. Mater., 133 (1994) p.437-439.